

## **Search Notes**



**Application/Control No.**

10/661.736

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**Examiner**

Richard H. Kim

**Applicant(s)/Patent under  
Reexamination**

LAI, CHUAN DE

## **Art Unit**

2871

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

# INTERFERENCE SEARCHED